

Wide bandwidth JFET Input Operational Amplifier in bare die form

Description

The SiS1057 JFET input amplifier combines precision specifications with high speed performance. A slew rate of 50V/µs with 1.5 µs settling time to 0.01% is suited for high speed sample + hold circuits and data converters. Low bias current and offset characteristics benefit applications requiring greater precision at speed, such as peak detectors, photodiode amplifiers and log amplifiers. The device exhibits low voltage and current noise at either high or low source impedance. Low drift over temperature delivers improved stability. This device is characterised over the full military temperature range.

Ordering Information

The following part suffixes apply:

- No suffix MIL-STD-883 /2010B Visual Inspection
- "H" MIL-STD-883 /2010B Visual Inspection + MIL-PRF-38534 Class H LAT
- "K" MIL-STD-883 /2010A Visual Inspection (space)
 + MIL-PRF-38534 Class K LAT

LAT = Lot Acceptance Test.

For further information on LAT process flows see below.

www.siliconsupplies.com\quality.bare-die-lot-qualification

Supply Formats:

- Defaut Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape On request
- Unsawn Wafer On request
- Die Thickness <> 460µm(18 Mils) On request
- Assembled into Ceramic Package On request

Features:

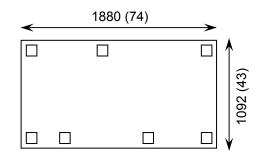
- Wide gain bandwidth: 20MHz ($A_V = 5$)
- High speed: 50V/µs slew rate, 1\5 µs settling time

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- Low noise: 12nv/√Hz (10KHs
- Low input bias current: S0pA
- Low drift input offset voltage: 1mV, 3µV/°C
- Common-Mode Rejection: 100 dB
- Open-Loop gain. 106 dB
- Differential upput voltage range ≤ supply voltage

Die Dimensions in µm (mils)

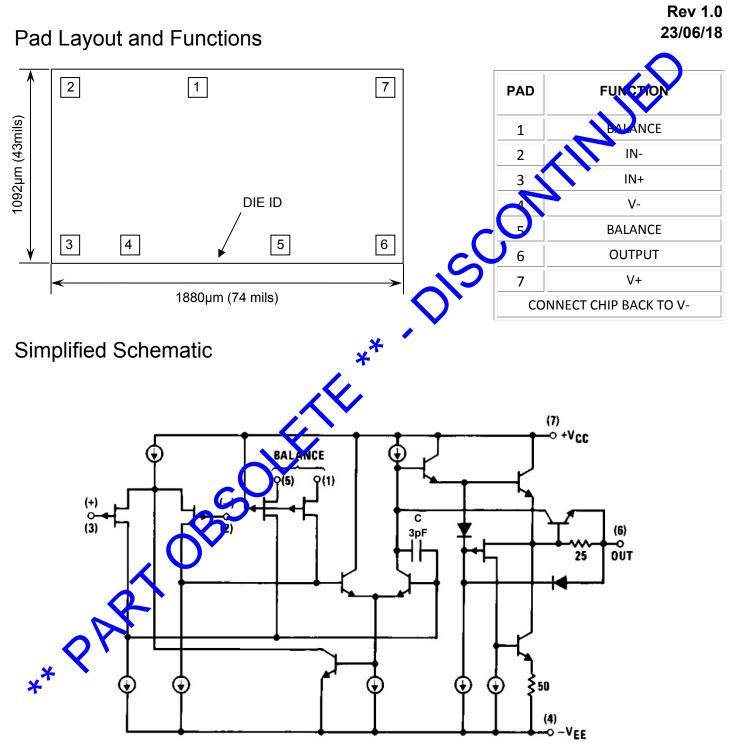


Mechanical Specification

Die Size	1880 x 1092 74 x 43	µm mils	
Minimum Bond Pad Size	100 x 100 4 x 4	µm mils	
Die Thickness	460 (±20) 18 (±0.79)	µm mils	
Top Metal Composition	Al 1%Si 1.1µm		
Back Metal Composition	N/A – Bare Si		









Absolute Maximum Ratings¹

0							
PARAMETER	SYMBOL	VALUE	UNIT				
Supply Voltage	Vs	±22	V				
Input Differential Voltage Range	V _{IDR}	±40					
Input Voltage Range ²	VI	±20					
Output Short Circuit to Ground	-	Continuous	-				
Electrostatic Discharge ³	V _{ESD}	±1000	V				
Power Dissipation in Still Air	PD	570	mW				
Storage Temperature	T _{STG}	-65 to +150	°C				
Junction Temperature	TJ	100	°C				

1. Operation above the absolute maximum rating may cause device failure. Operation at the absolute maximum ratings, for extended periods, may reduce device reliability.

2. Unless otherwise specified the absolute maximum negative input voltage is equal to the leastive power supply voltage.

3. 100 pF discharged through 1.5-k Ω resistor, Human body model (HBM).

Recommended Operating Conditions

PARAMETER	SYMBOL	MIN	MAX	UNITS
DC Supply Voltage	V _{CC}	≱ ¶5	±20	V
Operating Temperature	TJ	-55	+125	°C
		\mathbf{V}		

DC Electrical Characteristics 53° C \leq T_J \leq +125°C, ±15V \leq V_S \leq ±20V unless otherwise specified)

PARAMETER	SYMBOL	CONDITIONS		LIMITS			UNITS
FARAMETER	STWBOL			MIN	ТҮР	MAX	UNITS
Input Offset Voltage V _{IO}	V	Γ _S = 50Ω,	25°C	-	1	2	mV
	V _{IO} V _{CM} = 0V	О V _{см} = 0V	125°C	-	-	2.5	
Input Offset Voltage Drift		R _S = 50Ω, V _{CM} = 0V		-	3	5	µV/°C
Change in Drift with V _{os} adjust⁴	ΔTC 7 V _{IO}			-	0.5	-	μV/°C per mV
	Input Offset Current I_{IO} $V_{CM} = 0V$	25°C	-	3	10	pА	
		v _{CM} – 0 v	v _{см} – 0v 125°С	-	-	10	nA
Input Bias Current⁵	Current ⁵ I_{IB} $V_{CM} = 0V$	$\gamma = 0 \gamma$	25°C	-	30	50	рА
		125°C	-	-	25	nA	
Supply Current	I _{CC}	$V_s = \pm 15V$	25°C	-	5	6	mA
Common Mode Input Voltage range	V _{ICR}	V _s = ±15V		±11	+15.1 -12	-	V

4. Temperature Coefficient of the adjusted input offset voltage changes 0.5mV/°C typically for each mV of adjustment from it's original unadjusted value. Common-mode rejection and open loop voltage gain are unaffected by offset adjustment.

5. In normal operation junction temperature rises above ambient temperature as a result of internal power dissipation, Pd. $T_J = T_A + \theta_J A$, where $\theta_J A$ is the thermal resistance from junction to ambient. Use of a heat sink is recommended to minimalize input bias current.



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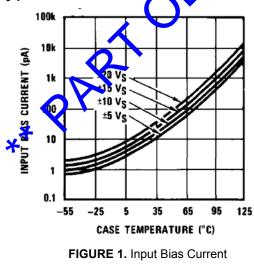
DC Electrical Characteristics (-55°C \leq T_J \leq +125°C, ±15V \leq V_S \leq ±20V unless otherwise specified)

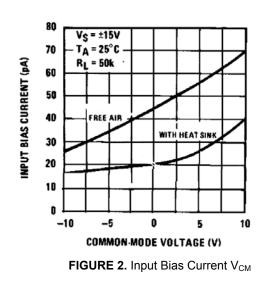
PARAMETER	SYMBOL	CONDITIONS		LIMITS			
	STMBOL CONDITIONS		MIN	TYP	MAX		
Input Resistance	R _{IN}	T _J = 25°C		-	10 ¹²	-	Ω
Large-Signal Open- Loop Voltage Gain	Δ	V _S = ±15V, V _O = ±10V,	25°C	50	200	-	V/mV
	$\begin{array}{c c} A_{VOL} & V_0 = \pm 10V, \\ R_L \ge 2K\Omega \end{array}$	-	125°C	50	-	. ~	V/IIIV
Output Voltage Swing	V	$V_{O} = \frac{V_{S} = \pm 15V, R_{L} = 10K\Omega}{V_{S} = \pm 15V, R_{L} = 2K\Omega}$		±12	±13	-	- V
	V0			±10	±12	-	
Common-Mode Rejection Ratio	CMRR			85	160	-	dB
Power Supply Rejection Ratio	PSSR			85	100	-	dB

AC Electrical Characteristics ($T_J = 25^{\circ}C$, $V_s = \pm 15V$ unless otherwise specified)

PARAMETER SYMBOL CONDITIONS		LIMITS			UNITS	
	STWIDOL		MIN	TYP	MAX	UNITS
Slew Rate	SR	A _V = 5	40	50	-	V/µs
Gain Bandwidth	GBW		15	20	-	MHz
Settling Time	ts	A _V = -5, 10) Step 0.01%	-	1.5	-	μS
Equivalent Input	•	$R_s = 100Q$ $t_0 = 100Hz$	-	15	-	nV/√Hz
Noise Voltage	en	$f_0 = 1 \text{ KHz}$	-	12	-	
Equivalent Input	i	P 1000 f _o = 100Hz	-	0.01	-	pA/√Hz
Noise Current	Noise Current	$f_0 = 1 \text{KHz}$	-	0.01		
Input Capacitance	C _{IN}		-	3	-	pF

Typical DC Characteristics









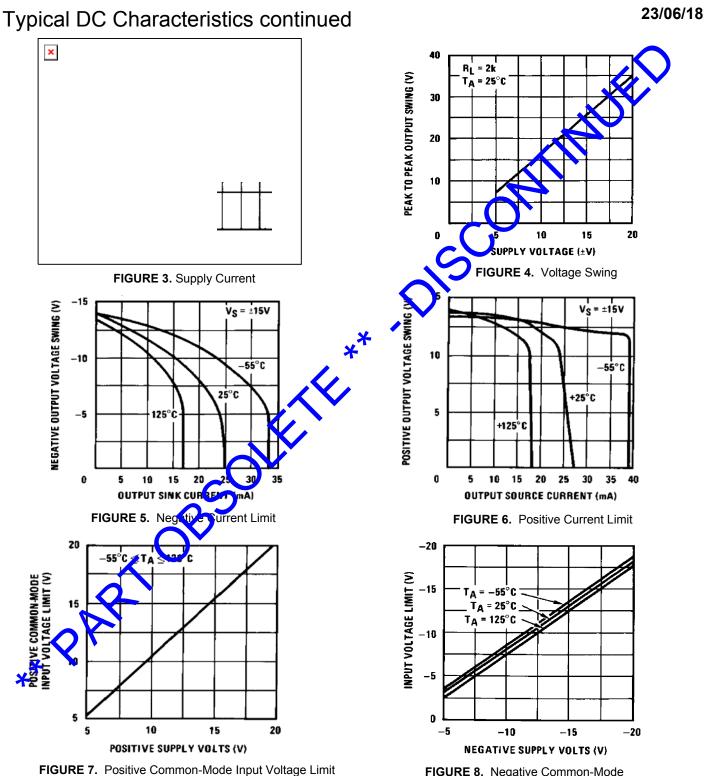
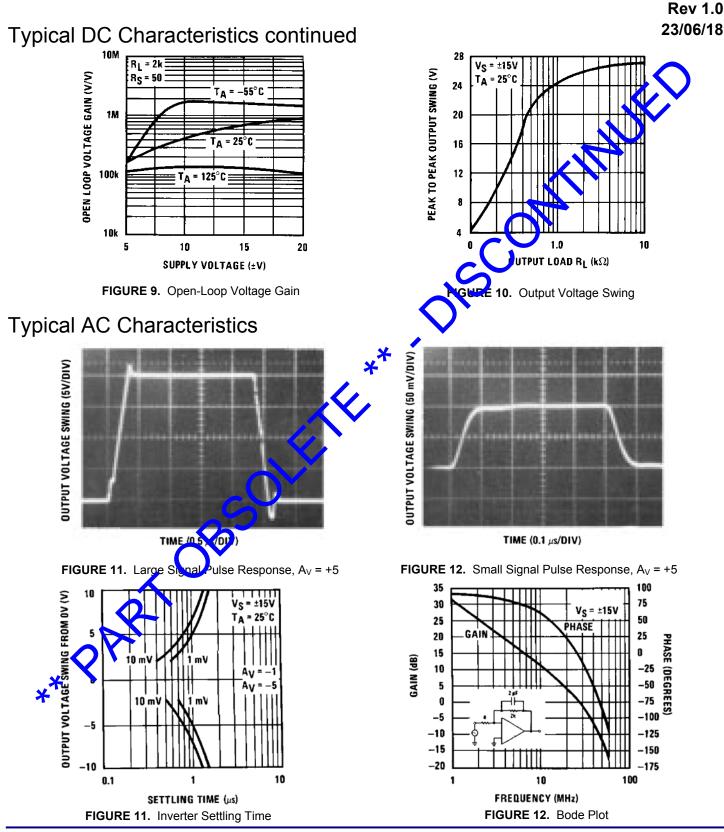


FIGURE 8. Negative Common-Mode Input Voltage Limit



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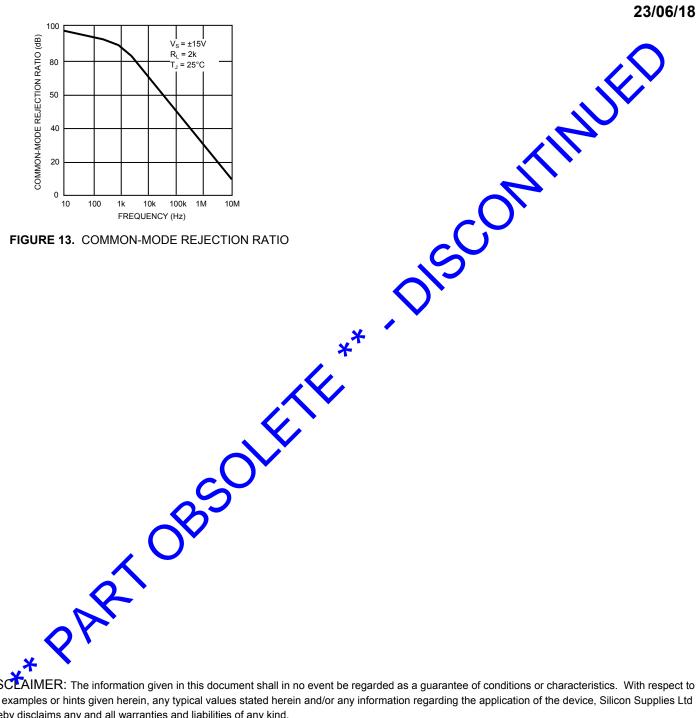


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